

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	2	"20040246791"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/22 01:49
S2	187526	memory adj device	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/21 10:02
S3	1330	S2 and memory adj core	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/21 10:02
S6	2	"6574757"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/21 10:11
S7	22767	nagata.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/21 10:11
S8	16658	kodama.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/21 10:11
S9	54	S7 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/03/21 10:11
S10	102361	semiconductor adj memory	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:31
S11	914	S10 and memory adj core	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:32
S12	192	S11 and redundant	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:39
S13	88	S12 and repair\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:34
S14	49	S13 and dimensional\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:37

S15	49	S14 and group	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:35
S16	2	S15 and first adj direction	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:35
S17	2	S15 and second adj direction	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:36
S18	2	S13 and two adj1 dimensional\$3 near2 group	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:37
S19	9	S11 and redundant adj line	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:41
S20	3	S19 and self adj1 test\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/06/13 03:41
S21	2	"20050007841"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/22 00:29
S22	2	"20040246791"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/22 00:30
S23	2	"20040208070"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/22 00:30
S24	6	S21 OR S22 OR S23	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/22 00:30
S25	2	"20050007841"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/28 02:11
S26	2	"20040246791"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/28 02:18

S27	2	"20040208070"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/28 02:11
S29	209193	memory adj device	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/28 03:03
S30	228	S29 and built\$in adj self near2 test near2 circuit	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/28 03:04
S31	77	S30 and redundant	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/28 03:04
S32	17	S30 and abnormal	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/11/28 03:04